

Large area CNT-Si heterojunction for photodetection

Carla Aramo for PARIDE Collaboration



Carla Aramo – INFN Napoli

Micro&Nano for photon detection

MACRO MICRO NANO



from Vacuum to Silicon to Carbon



Carla Aramo – INFN Napoli





Growth Mechanism of Carbon Nanotubes (CVD)







CNT

Characteristics

- External diameter: 15 25 nm
- Internal diameter: 5 10 nm
- Average number of nanotubes: 10 15







MWCNT photo absorbance





Sapphire prototype detector





The response of the MWCNT carpet to a monochromatic pulsed light, showing the highest and faster detection efficiency for the UV light. These characteristics make the material highly interesting for UV photodetection.



Main problems with sapphire photodetector

- 1. High dark current between metallic electrodes;
- 2. Low level of photocurrent (no signal amplification can be applied without amplifying the dark current also).





Drain Voltage (V)

The use of a layered silicon substrate permits to collect the generated photocurrent through the silicon avoiding the surface dark current.

Solution: create a MWCNT-Si photosensitive heterojunction in which CNTs film converts photons into electrons and the layered silicon substrate amplify the signal by means of a secondary dicharge.





Istituto Nazionale di Fisica Nucleare

I N F N

VCI Vienna, February 15-19, 2016

Carla Aramo – INFN Napoli



The device substrate has the structure of a Metal-Insulator-Silicon (MIS) photodiode: applying an external electrical field between the two electrodes on the front and on the back of silicon layer and operating voltage sweeps the dark current assumes a straighten behavior typical of a diode.



Large area MWCNT-Si radiation detector



The application of voltage sweeps to the device generates the heterojunction between CNT and silicon substrate: the dark current measured between electrodes in the front and in the back of device assumes a threshold behavior.



An electrical field can be applied between the two sides of device obtaining a large area photodiode whose equivalent circuit is depicted in figure, where D is the device, I_L is the photocurrent generated by the incident light, Cj is the heterojunction capacity, R_{sh} the shunt resistance and R_s the circuit resistance.



The heterojunction is characterized by a well defined threshold at 2.4 V completely absent in the substrate without CNTs. Dark current is about 2 nA for a surface of 0.5 cm^2

Photocurrent and linearity

0,40 0.40 FBK Fe 1.0 mW 1.0 mW . **FBK** Ni 0,35 0.35 0.9 mW 0.9 mW 0.8 mW 0.8 mW 0.30 0.30 0.7 mW 0.7 mW Photocurrent (mA) Photocurrent (mA) $0.6 \,\mathrm{mW}$ 0,25 0.6 mW 0.25 0.5 mW 0.5 mW 0.20 0,20 0.4 mW 0.4 mW 0.3 mW 0.3 mW 0,15 0.15 0.2 mW 0.2 mW 0.10 0.1 mW 0,10 0.1 mW Dark 0.05 0,05 0.00 0.00 -0.05 -0,05 10 15 20 0 5 20 25 30 -10 -5 5 10 15 0 Voltage (V) Voltage (V) 1.2 **Room temperature** No electronics 1.0 No signal amplification 0.8 Power (mW) Long and stable plateau Linearity I vs P 405 nm 532 nm Threshold 650 nm 685 nm No saturation observed 808 nm 0.2 Uniformity on all the CNT surface 880 nm 980 nm Long term stability (>8 years) 0.0 0.08 0.12 0.16 0.20 0.00 0.04 0.24 0.28 Breakdrown @ >100 V Photocurrent (mA)

685 nm light emitting diode (LED) laser



Carla Aramo – INFN Napoli



The quantum efficiency (QE) of the device was estimated as the ratio of the number of electrons collected at plateau (I) to the number of incident photons according to the relation:

$$\mathsf{QE} \pm \sigma_{QE} = \frac{hcl}{\lambda eP} \pm \frac{hc}{e} \sqrt{\left(\frac{1}{\lambda P}\right)^2 \sigma_l^2 + \left(\frac{l}{\lambda^2 P}\right)^2 \sigma_\lambda^2 + \left(\frac{l}{P^2 \lambda}\right)^2 \sigma_P^2}$$



Quantum efficiency of CNTs with Ni catalyst appears much higher than that of CNTs with Fe catalyst, especially in the UV and IR regions.



Tunnel effect



The shape of the current-voltage curve presents a negative differential resistance and resembles that of a resonant tunneling junction.

These observations clearly indicate that impinging light and, as a consequence, the photogenerated charges play a fundamental role in the heterojunction behaviour.

The current shape similarity with that of typical resonant tunneling junction suggests that a kind of electronic resonance process induced by the photogenerated charges may be present.

Resonant tunnel-like current is generated only under light radiation and it is function of the wavelength as well as of the power intensity

Study of heterojunction MWCNT-Si



Contents lists available at ScienceDirect

Nuclear Instruments and Methods in Physics Research A

NUCLEAR INSTRUMENTS A METHODS IN PHYSICS RESEARCH

journal homepage: www.elsevier.com/locate/nima

Electrical analysis of carbon nanostructures/silicon heterojunctions designed for radiation detection

A. Tinti^{a,*}, F. Righetti^a, T. Ligonzo^a, A. Valentini^a, E. Nappi^a, A. Ambrosio^b, M. Ambrosio^c, C. Aramo^c, P. Maddalena^b, P. Castrucci^d, M. Scarselli^d, M. De Crescenzi^d, E. Fiandrini^e, V. Grossi^f, S. Santucci^f, M. Passacantando^f

^a INFN, Sezione di Bari, Via Amendola 173, 70126 Bari, Italy

^b CNR-SPIN U.O.S. di Napoli e Dipartimento di Scienze Fisiche, Universitá degli Studi di Napoli Federico II, Via Cintia 2, 80126 Napoli, Italy

^c INFN, Sezione di Napoli, Via Cintia 2, 80125 Napoli, Italy

- ^d Dipartimento di Fisica, Università degli Studi di Roma Tor Vergata, Via della Ricerca Scientifica 1, 00133 Roma, Italy
- e INFN, Sezione di Perugia e Dipartimento di Fisica, Università degli Studi di Perugia, Piazza Università 1, 06100 Perugia, Italy

[†] Dipartimento di Fisica, Università degli Studi dell'Aquila, Via Vetoio 10, 67100 Coppito, L'Aquila, Italy

Nuclear Instruments and Methods in Physics Research A 629 (2011), 377-381

Keywords: Carbon nanotuber

ABSTRACT

A new class of radiation detectors based on carbon nanostructures as the active photosensitive element has been recently developed. In this scenario the optimization of the device, both in dark and on light irradiation, is a crucial point. Here, we report on electrical measurements performed in dark conditions on carbon nanofibers and nanotubes deposited on silicon substrates. Our experimental results were interpreted in terms of <u>a multistep tunneling process occurring at the carbon nanostructures/silicon</u> interface.

© 2010 Elsevier B.V. All rights reserved.



Key point \rightarrow how the hetero-junction creates?



The presence of the insulator is bypassed by the formation of permanent low resistivity conduction channels which are created as an external voltage is applied to the device thanks to the peculiar characteristics of the nanotubes to appear as unidimensional elements.



The C-V plot indicates the change of capacitance at the same drain voltage threshold of 2.4 V. The MWCNTs act as a semi-metallic layer, the silicon substrate is ndoped and the nitrite layer is the pierced insulating dielectric.



Phototransistor-like device configuration



Depletion regions amplitude depends on the applied voltage. The silicon bulk, 625 μ m thick, can be considered as a passive resistance except in the depletion areas.

The MIS depletion area cannot be reached from optical radiation because of the presence of metal.

Instead the depletion area created by the CNT-Si heterojunction can be reached and activated by the radiation due to the nanotube characteristics. A light's fraction is absorbed inside CNT and converted in hole-electron pairs or excitons. The other reaches silicon and is converted inside.

The described device can be considered as a "phototransistor"





Key points of a CNT-Si photodetector



- 1. A large area photodetector build by simply growing CNTs on a n-type silicon substrate;
- 2. a CNT-Si heterojunction is created applying voltage sweeps to the electrodes;
- 3. the device presents a great uniformity over all the sensitive area;
- 4. QE and photoresponsivity are comparable to that of commercial photodiode;
- 5. charge collected presents a great linearity and saturation effects have been observed;
- 6. photosensistivity extends in a wide wavelength range, from UV to IR;
- 7. the device can be used both to detect continuous and pulses light;
- at present no amplification can detect light pulses with large number of photons (>10⁴)







Signal vs drain voltage @ 81nJ



The signal shape strongly depends from the CNT catalyst and from the laser light intensity, less from the drain voltage applied.

The incident radiation excites CNTs energetic levels and the drain voltage collects the generated charge. No saturation effects have been observed.





- The MWCNTs with Ni catalyst shows an higher charge generation than Fe.
- In spite of the high light intensity the photodetector charge is linear for all drain voltage range and not in saturation.
- The charge distributions are well separeted for all drain voltage range.







SiPM_CNT Project

6 mm QUAD

 SiPMs based on FBK NUV-HD technology and specifically designed for CNT

6 mm

Typical specs of the standard NUV-HD SiPMs

Typical Parameters (@ room T)	NUV-HD CS = 25um
Cell Size	25 µm
Fill Factor	73%
Breakdown Voltage	26.5 V
Max PDE	50%
Peak PDE λ	410 nm
DCR (20°C)	< 150 kHz/mm ²
DiCT	25%
DeCT + AP	2%







AND IMAGE SENSOR:



AND IMAGE SENSORS

Main Scientific Challenges

- ✓ Increase quantum efficiency due to the photoresponsivity enhancement from MWCNT absorbance, in the wavelength range 200-400 nm.
- ✓ Decrease dark noise thanks to heterojunction MWCNT/Si → increase the device area (cm² or more VS mm² SiPM).
- ✓ MWCNT bottom-up technology → cells (pad or strip) hundreds of nm up to mm VS 15 µm up to 100 µm for SiPM.







✓ Maximizes the sensitive area for photoconversion and its uniformity → Electric field applied via a conductive coating.





Light absorption



The CNT layer absorbs UV photons producing photoelectrons that can be transferred by means of an external electrical field inside the depletion zone of the hetero-junction. Therefore the charge induces a photocurrent drained out by the applied voltage.







Nano-pixelled photocathodes sensitive to the UV radiation may be obtained by means of nanolithography in a very cheap and easy way!

EHT = 10.00 kV

WD = 6 mm







Building nano - detecting micro





Thank you for attention











CNT energetic levels

Semiconductors nanotubes show interesting fluorescence properties in the region of close infrared (from ~ 1 to ~ 15 μ m) tied to their electronic characteristics. <u>Nanotubes of type n-m=3p with p entire</u> <u>positive or null are metallic conductors</u>.

All the others are semiconductors whose gap is function of the diameter, and are approximated from the function:

$$E_{gap}=2 y_0 acc/d$$

where $y_0=0.1 \text{ eV}$, acc=0.142 nm and d is the diameter. This implies that for the Single Wall CNT the fundamental gap varies from 0.4 to 0.7 eV.

Multi Wall CNT instead present a wider range of energy gap.



Semiconducting Zig-zag

Armchair



R. Saito, G. Dresselhaus and M.S. Dresselhaus, Physical Properties of Carbon Nanotubes, Imperial College Press (2003)









Great uniformity over large area



The electric field applied uniformly over the entire CNT surface plays a fundamental rule making uniform the charge electrodes.

The signal generated everywhere in the sample can be collected to the metallic electrodes through the ITO layer, whose resistivity is very low.



Si-CNT photodetector responsivity



Responsivity comparison between Si-CNT prototype and commercial photodiode



Si-CNT photoresponsivity



A particular layered substrate without the schottky junction on the back shows very peculiar characteristics: high quantum efficency in all the wide wavelength range, a hetero-junction threshold at 2.5 V and a well defined tunnel effect under this voltage. Work on this substrate is still in progress.

